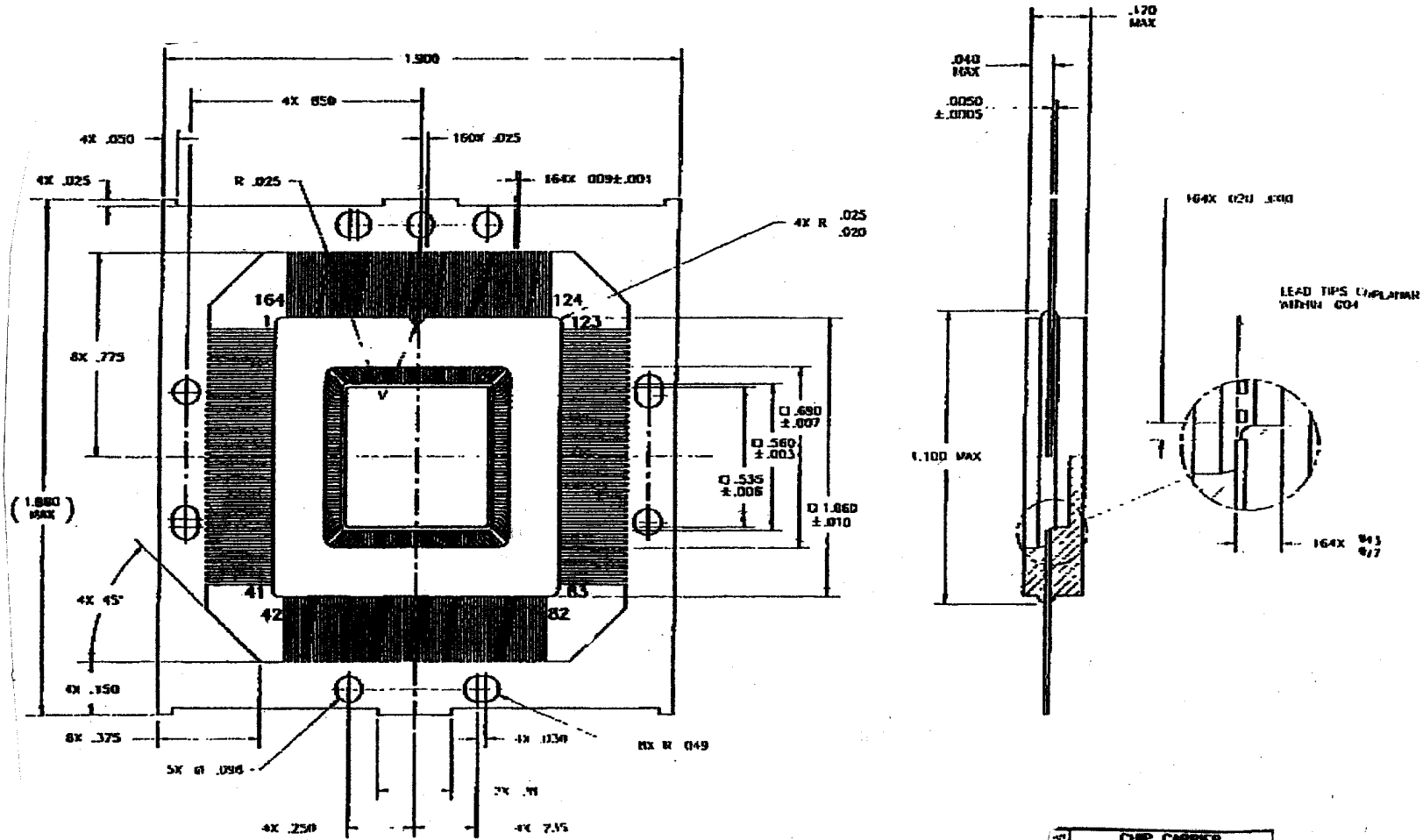


SSM P/N CQF16401

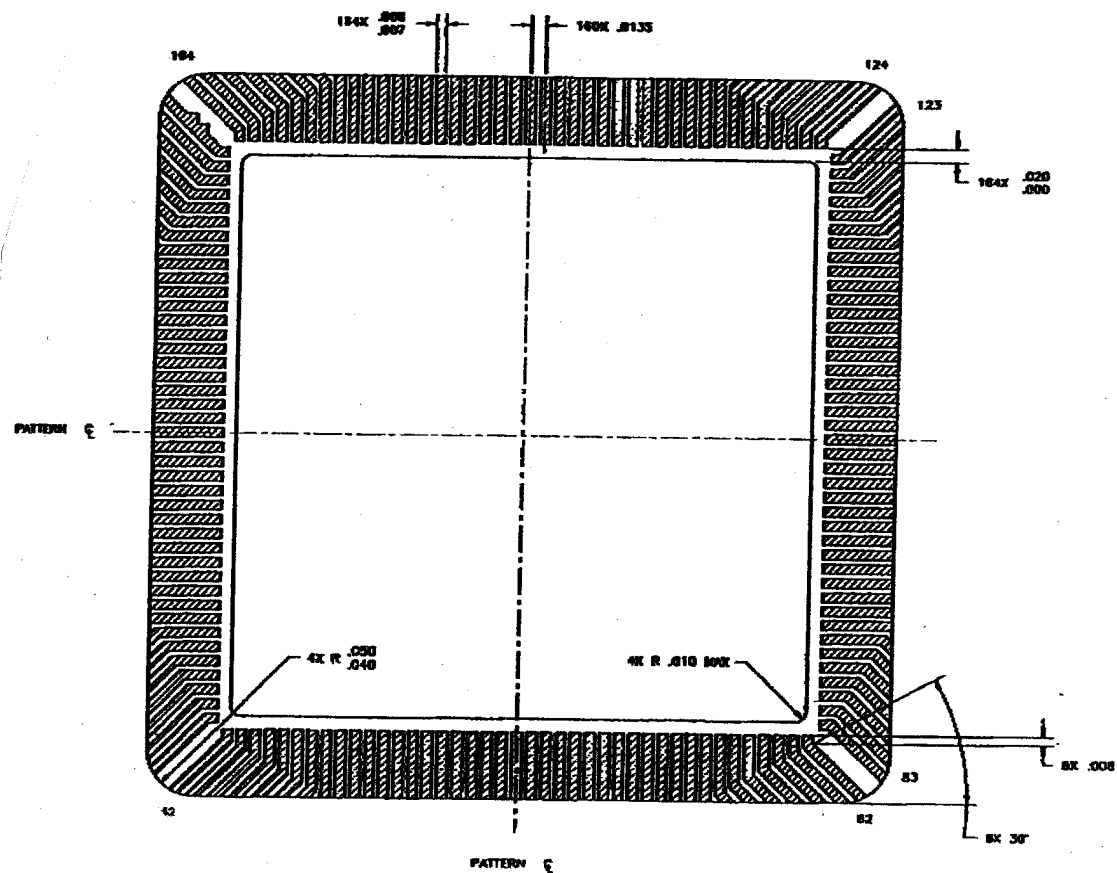


CHIP CARRIER,  
164 LEAD, .535 CAVITY  
DWG. NO. 30916401



www.spectrum-semi.com Phone: 408-435-5555 Fax: 408-435-8226

SSM P/N CQF16401



CAVITY DETAIL



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## SSM P/N CQF16401

PACKAGE SPECIFICATION: 164LD COFP, .535 CAV., .025 PITCH (SP164CQ.TXT, rev.1)

### I. Material:

- A. Substrate: Ceramic, 90-96% alumina, opaque.
- B. Metallization:
  - 1. Leads, external and internal: Must be Alloy 42 or approved equivalent.
- C. Sealing Glass.
  - 1. Glass compound shall be Owens Illinois CV-111.

### II. Plating:(Base metal finish)

- A. Internal lead (wire bond posts) shall be Aluminum deposition.
  - 1. Thickness, 200 microinches (5.08 micrometers) minimum, 800 microinches (20.32 micrometers) maximum.
  - 2. Thickness shall be measured at the center of the lead (wire bond posts).

### III. Metallization:

- A. No screened metallization will be done on this package.
  - 1. Die attach area is bare alumina.
  - 2. Seal ring area is bare alumina.

### IV. Electrical:

- A. Lead Resistance:
  - 1. 0.30 ohms maximum.
  - 2. All leads.
  - 3. Measured from center of wire bond post to the lead, within .100" of the tip of the lead.

### V. Mechanical:

- A. Package ceramic and sealing glass, must have no cracks, delaminations or foreign material visible at 20X.
- B. Assembled packages must pass the following tests per Mil-Std-883.
  - 1. Salt Atmosphere: Method 1009.6, condition A min.
  - 2. External Visual: Method 2009.8 (if not specifically mentioned elsewhere).
  - 3. Lead Integrity: Method 2004.5, condition B2.
- C. Coplanarity.
  - 1. Wire bond posts: .004"
    - a. Measurement location; along post, from tip, +.004" to .015"; across post, 66% of width.
- D. External lead surface condition.
  - 1. The leads shall have no contaminant or condition that will inhibit a standard Sn (tin) plating process.
- E. Glass Seal.
  - 1. The glass shall be fired completely, to eliminate moisture release in subsequent process.
  - 2. The glass shall be fired such that any residual metallic material on the surface will not cause electrical bridging initially or after Sn (tin) plating.

